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About the Author

Allen Mann received his BS in physics at UCLA in 1961. He has 48 years of experience in the design and analysis of a wide variety of optical systems, including visual and infrared zoom lenses. He was first employed as an optical designer at the Infrared Laboratory of Lockheed Aircraft Corporation. His subsequent positions were with Northrop Nortronics, Xeros Electro-Optical Systems, and Ford Aeronutronic. He has written several papers on the subject of infrared zoom lenses and is the editor for the SPIE Milestone volume *Selected Papers on Zoom Lenses*. He was chairman of SPIE Zoom Lens Conference I and co-chair of Zoom Lens Conference II. Mann retired from Hughes Aircraft Company in 1992 and is now an independent consultant. He teaches the SPIE short course on infrared zoom lenses and is a member of SPIE and the Optical Society of America.